

Search Notes

Application/Control No.

10/813,093

Examiner

Dwayne J. White

Applicant(s)/Patent under
Reexamination

SUN, SUNG-WEI

Art Unit

3745

SEARCHED

Class	Subclass	Date	Examiner
415	193		
	199.4		
	199.5		
	208.2		
	209.4		
416	185		
	188		
	193R		
	196R		
	247R		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR